

Semiconductor devices — Mechanical and climatic test methods —

Part 25: Temperature cycling

The European Standard EN 60749-25:2003 has the status of a British Standard

ICS 31.080.01

National foreword

This British Standard is the official English language version of EN 60749-25:2003. It is identical with IEC 60749-25:2003. It partially supersedes BS EN 60749:1999 which will be withdrawn on 2006-09-01.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors, which has the responsibility to:

- aid enquirers to understand the text;
- present to the responsible international/European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
- monitor related international and European developments and promulgate them in the UK.

A list of organizations represented on this committee can be obtained on request to its secretary.

Cross-references

The British Standards which implement international or European publications referred to in this document may be found in the *BSI Catalogue* under the section entitled “International Standards Correspondence Index”, or by using the “Search” facility of the *BSI Electronic Catalogue* or of British Standards Online.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

Compliance with a British Standard does not of itself confer immunity from legal obligations.

This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 October 2003

Summary of pages

This document comprises a front cover, an inside front cover, the EN title page, pages 2 to 13 and a back cover.

The BSI copyright notice displayed in this document indicates when the document was last issued.

Amendments issued since publication

Amd. No.	Date	Comments